



## **HV Diffractometer** < RDM-10 >



This diffractometer was manufactured for research of solid surfaces and thin film surfaces and interfaces. To observe the X-rays diffracted from the surface of a sample in any direction, this instrument has a four-axis structure comprising 2+2 axes.

With an ultra-high vacuum tank that allows on-the-spot observation, the axes are assembled so that the displacement of the rotating centers is less than 50µm. The UHV diffractometer has two degrees of freedom (DOF) on the sample and two independent DOF on the detector. The diffractometer is about 3.2 m x 3.2 m x 2.3 m in dimension. This instrument is now in service in the SPring-8 (Super Photon ring-8 GeV) BL13XU in Japan.